Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/624,506	BYEON ET AL.
Examiner	Art Unit
Edward Wojciechowicz	2815

SEARCHED				
Class	Subclass	Date	Examiner	
757	343 390 391,370 396	4-27-05	981	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		-		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST 75) 343,390,391,392 Dmos; Lod	4.205	ED	